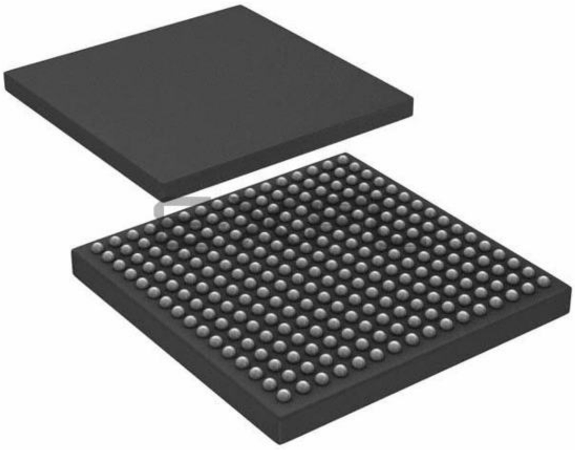


Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	6036
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	203
Number of Gates	108000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	256-LBGA
Supplier Device Package	256-FPBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx72a-fgg256m

Ordering Information

A54SX16A 2 PQ G 208 __

Application (Temperature Range)
Blank = Commercial (0 to +70°)
I = Industrial (-40 to +85°C)
A = Automotive (-40 to +125°C)
M = Military (-55 to +125°C)
B = MIL-STD-883 Class B

Package Lead Count

Package Type
BG = 1.27 mm Plastic Ball Grid Array
FG = 1.0 mm Fine Pitch Ball Grid Array
PQ = Plastic Quad Flat Pack
TQ = Thin (1.4 mm) Quad Flat Pack
CQ = Ceramic Quad Flat Pack[1]

Speed Grade
Blank = Standard Speed
–1 = Approximately 15% Faster than Standard
–2 = Approximately 25% Faster than Standard
–3 = Approximately 35% Faster than Standard[2]
–F = Approximately 40% Slower than Standard

Part Number
A54SX08A = 12,000 System Gates
A54SX16A = 24,000 System Gates
A54SX32A = 48,000 System Gates
A54SX72A = 108,000 System Gates

Notes:

1. *For more information about the CQFP package options, refer to the* HiRel SX-A datasheet*.*
2. *All –3 speed grades have been discontinued.*

Device Resources

	User I/Os (Including Clock Buffers)							
Device	**208-Pin PQFP**	**100-Pin TQFP**	**144-Pin TQFP**	**176-Pin TQFP**	**329-Pin PBGA**	**144-Pin FBGA**	**256-Pin FBGA**	**484-Pin FBGA**
A54SX08A	130	81	113	–	–	111	–	–
A54SX16A	175	81	113	–	–	111	180	–
A54SX32A	174	81	113	147	249	111	203	249
A54SX72A	171	–	–	–	–	–	203	360

Notes: *Package Definitions: PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array, FBGA = Fine Pitch Ball Grid Array*

Table of Contents

Logic Module Design

The SX-A family architecture is described as a "sea-of-modules" architecture because the entire floor of the device is covered with a grid of logic modules with virtually no chip area lost to interconnect elements or routing. The Actel SX-A family provides two types of logic modules: the register cell (R-cell) and the combinatorial cell (C-cell).

The R-cell contains a flip-flop featuring asynchronous clear, asynchronous preset, and clock enable, using the S0 and S1 lines control signals (Figure 1-2). The R-cell registers feature programmable clock polarity selectable on a register-by-register basis. This provides additional flexibility while allowing mapping of synthesized functions into the SX-A FPGA. The clock source for the R-cell can be chosen from either the hardwired clock, the routed clocks, or internal logic.

The C-cell implements a range of combinatorial functions of up to five inputs (Figure 1-3). Inclusion of the DB input and its associated inverter function allows up to 4,000 different combinatorial functions to be implemented in a single module. An example of the flexibility enabled by the inversion capability is the ability to integrate a 3-input exclusive-OR function into a single C-cell. This facilitates construction of 9-bit parity-tree functions with 1.9 ns propagation delays.

Module Organization

All C-cell and R-cell logic modules are arranged into horizontal banks called Clusters. There are two types of Clusters: Type 1 contains two C-cells and one R-cell, while Type 2 contains one C-cell and two R-cells.

Clusters are grouped together into SuperClusters (Figure 1-4 on page 1-3). SuperCluster 1 is a two-wide grouping of Type 1 Clusters. SuperCluster 2 is a two-wide group containing one Type 1 Cluster and one Type 2 Cluster. SX-A devices feature more SuperCluster 1 modules than SuperCluster 2 modules because designers typically require significantly more combinatorial logic than flip-flops.

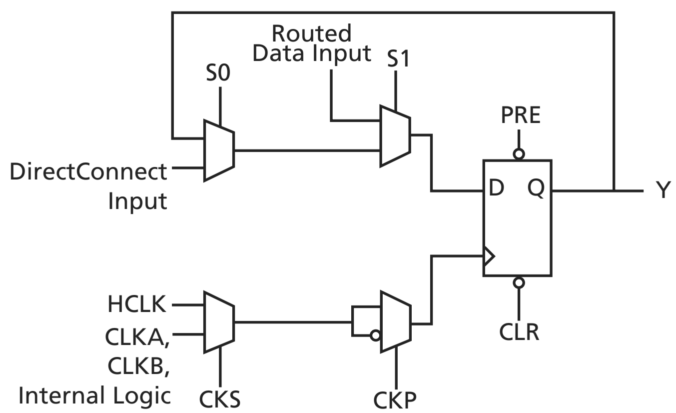


Figure 1-2 • **R-Cell**

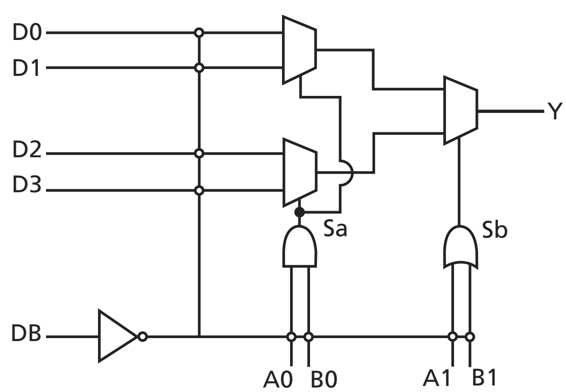


Figure 1-3 • **C-Cell**

JTAG Instructions

Table 1-7 lists the supported instructions with the corresponding IR codes for SX-A devices.

Table 1-8 lists the codes returned after executing the IDCODE instruction for SX-A devices. Note that bit 0 is always '1'. Bits 11-1 are always '02F', which is the Actel manufacturer code.

Table 1-7 • **JTAG Instruction Code**

Instructions (IR4:IR0)	Binary Code
EXTEST	00000
SAMPLE/PRELOAD	00001
INTEST	00010
USERCODE	00011
IDCODE	00100
HighZ	01110
CLAMP	01111
Diagnostic	10000
BYPASS	11111
Reserved	All others

Table 1-8 • **JTAG Instruction Code**

Device	Process	Revision	Bits 31-28	Bits 27-12
A54SX08A	0.22 µ	0	8, 9	40B4, 42B4
		1	A, B	40B4, 42B4
A54SX16A	0.22 µ	0	9	40B8, 42B8
		1	B	40B8, 42B8
	0.25 µ	1	B	22B8
A54SX32A	0.2 2µ	0	9	40BD, 42BD
		1	B	40BD, 42BD
	0.25 µ	1	B	22BD
A54SX72A	0.22 µ	0	9	40B2, 42B2
		1	B	40B2, 42B2
	0.25 µ	1	B	22B2

SX-A Probe Circuit Control Pins

SX-A devices contain internal probing circuitry that provides built-in access to every node in a design, enabling 100% real-time observation and analysis of a device's internal logic nodes without design iteration. The probe circuitry is accessed by Silicon Explorer II, an easy to use, integrated verification and logic analysis tool that can sample data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

The Silicon Explorer II tool uses the boundary-scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-13 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

In order to preserve device probing capabilities, users should avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, critical input signals through these pins are not available. In addition, the security fuse must not be programmed to preserve probing capabilities. Actel recommends that you use a 70 Ω series termination resistor on every probe connector (TDI, TCK, TMS, TDO, PRA, PRB). The 70 Ω series termination is used to prevent data transmission corruption during probing and reading back the checksum.

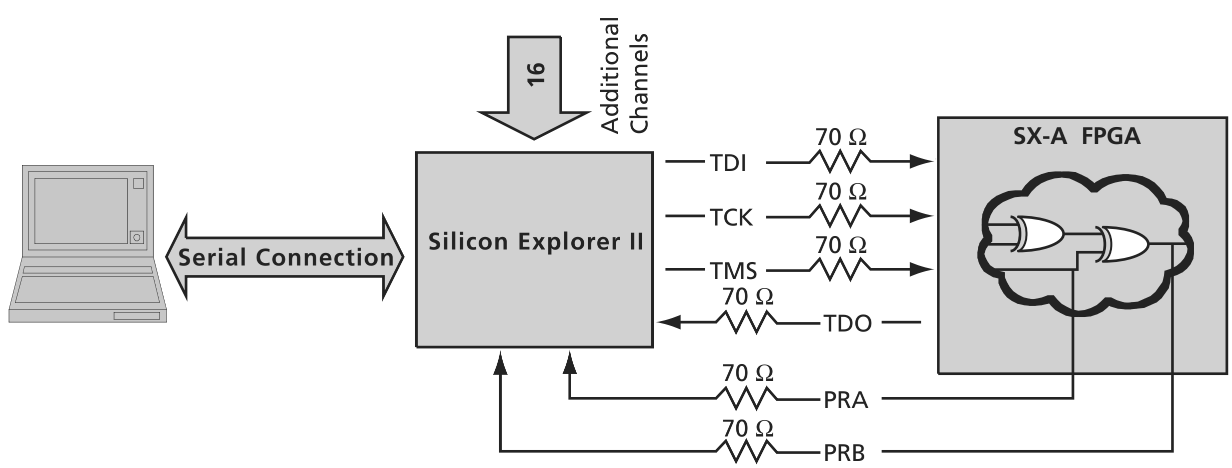


Figure 1-13 • **Probe Setup**

Design Environment

The SX-A family of FPGAs is fully supported by both Actel Libero® Integrated Design Environment (IDE) and Designer FPGA development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Additionally, Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw® for Actel from Mentor Graphics®, Model*Sim*® HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the *Libero IDE flow* diagram for more information (located on the Actel website).

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators and the simulation results can be cross-probed with Silicon Explorer II, Actel's integrated verification and logic analysis tool. Another tool included in the Designer software is the SmarGen core generator, which easily creates popular and commonly used logic functions for implementation in your schematic or HDL design. Actel's Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys, and Cadence Design Systems. The Designer software is available for both the Windows and UNIX operating systems.

Programming

Device programming is supported through Silicon Sculptor series of programmers. In particular, Silicon Sculptor is compact, robust, single-site and multi-site device programmer for the PC.

With standalone software, Silicon Sculptor allows concurrent programming of multiple units from the same PC, ensuring the fastest programming times possible. Each fuse is subsequently verified by Silicon Sculptor II to insure correct programming. In addition, integrity tests ensure that no extra fuses are programmed. Silicon Sculptor also provides extensive hardware self-testing capability.

The procedure for programming an SX-A device using Silicon Sculptor is as follows:

1. Load the .AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Actel offers device volume-programming services either through distribution partners or via in-house programming from the factory.

For detailed information on programming, read the following documents *Programming Antifuse Devices* and *Silicon Sculptor User's Guide*.

Related Documents

Application Notes

Global Clock Networks in Actel's Antifuse Devices
http://www.actel.com/documents/GlobalClk_AN.pdf
Using A54SX72A and RT54SX72S Quadrant Clocks
http://www.actel.com/documents/QCLK_AN.pdf
Implementation of Security in Actel Antifuse FPGAs
http://www.actel.com/documents/Antifuse_Security_AN.pdf
Actel eX, SX-A, and RTSX-S I/Os
http://www.actel.com/documents/AntifuseIO_AN.pdf
Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications
http://www.actel.com/documents/HotSwapColdSparing_AN.pdf
Programming Antifuse Devices
http://www.actel.com/documents/AntifuseProgram_AN.pdf

Datasheets

HiRel SX-A Family FPGAs
http://www.actel.com/documents/HRSXA_DS.pdf
SX-A Automotive Family FPGAs
http://www.actel.com/documents/SXA_Auto_DS.pdf

User's Guides

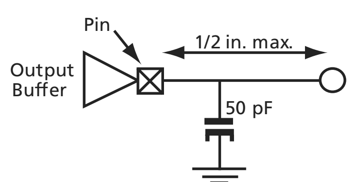
Silicon Sculptor User's Guide
http://www.actel.com/documents/SiliSculptII_Sculpt3_ug.pdf

Table 2-8 • **AC Specifications (5 V PCI Operation)**

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \le 1.4$ [1]	–44	–	mA
		$1.4 \le V_{OUT} < 2.4$ [1, 2]	$(-44 + (V_{OUT} - 1.4)/0.024)$	–	mA
		$3.1 < V_{OUT} < V_{CCI}$ [1, 3]	–	EQ 2-1 on page 2-5	–
	(Test Point)	$V_{OUT} = 3.1$ [3]	–	–142	mA
$I_{OL(AC)}$	Switching Current Low	$V_{OUT} \ge 2.2$ [1]	95	–	mA
		$2.2 > V_{OUT} > 0.55$ [1]	$(V_{OUT}/0.023)$	–	mA
		$0.71 > V_{OUT} > 0$ [1, 3]	–	EQ 2-2 on page 2-5	–
	(Test Point)	$V_{OUT} = 0.71$ [3]	–	206	mA
I_{CL}	Low Clamp Current	$-5 < V_{IN} \le -1$	$-25 + (V_{IN} + 1)/0.015$	–	mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load [4]	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load [4]	1	5	V/ns

Notes:

1. *Refer to the V/I curves in Figure 2-1 on page 2-5. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.*
2. *Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.*
3. *Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 2-1 on page 2-5. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.*
4. *This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.*



Thermal Characteristics

Introduction

The temperature variable in Actel Designer software refers to the junction temperature, not the ambient, case, or board temperatures. This is an important distinction because dynamic and static power consumption will cause the chip's junction to be higher than the ambient, case, or board temperatures. EQ 2-9 and EQ 2-10 give the relationship between thermal resistance, temperature gradient and power.

$$\theta_{JA} = \frac{T_J - T_A}{P}$$

EQ 2-9

$$\theta_{JA} = \frac{T_C - T_A}{P}$$

EQ 2-10

Where:

θ_{JA} = Junction-to-air thermal resistance

θ_{JC} = Junction-to-case thermal resistance

T_J = Junction temperature

T_A = Ambient temperature

T_C = Ambient temperature

P = total power dissipated by the device

Table 2-12 • **Package Thermal Characteristics**

Package Type	Pin Count	θ_{JC}	θ_{JA} Still Air	θ_{JA} 1.0 m/s 200 ft./min.	θ_{JA} 2.5 m/s 500 ft./min.	Units
Thin Quad Flat Pack (TQFP)	100	14	33.5	27.4	25	°C/W
Thin Quad Flat Pack (TQFP)	144	11	33.5	28	25.7	°C/W
Thin Quad Flat Pack (TQFP)	176	11	24.7	19.9	18	°C/W
Plastic Quad Flat Pack (PQFP)[1]	208	8	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack (PQFP) with Heat Spreader[2]	208	3.8	16.2	13.3	11.9	°C/W
Plastic Ball Grid Array (PBGA)	329	3	17.1	13.8	12.8	°C/W
Fine Pitch Ball Grid Array (FBGA)	144	3.8	26.9	22.9	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	256	3.8	26.6	22.8	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	484	3.2	18	14.7	13.6	°C/W

Notes:

1. *The A54SX08A PQ208 has no heat spreader.*
2. *The SX-A PQ208 package has a heat spreader for A54SX16A, A54SX32A, and A54SX72A.*

Table 2-21 • **A54SX16A Timing Characteristics (Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1] Min.	–3 Speed[1] Max.	–2 Speed Min.	–2 Speed Max.	–1 Speed Min.	–1 Speed Max.	Std. Speed Min.	Std. Speed Max.	–F Speed Min.	–F Speed Max.	Units
C-Cell Propagation Delays[2]												
t_{PD}	Internal Array Module		0.9		1.0		1.2		1.4		1.9	ns
Predicted Routing Delays[3]												
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.3		0.4		0.6	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.6	ns
t_{RD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{RD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{RD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1		1.4	ns
t_{RD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t_{RD12}	FO = 12 Routing Delay		1.7		2		2.2		2.6		3.6	ns
R-Cell Timing												
t_{RCO}	Sequential Clock-to-Q		0.6		0.7		0.8		0.9		1.3	ns
t_{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.6		0.8		1.0	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.7		0.8		0.8		1.0		1.4	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.3		1.5		1.6		1.9		2.7		ns
$t_{RECASYN}$	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t_{HASYN}	Asynchronous Removal Time	0.3		0.3		0.3		0.4		0.6		ns
t_{MPW}	Clock Minimum Pulse Width	1.4		1.7		1.9		2.2		3.0		ns
Input Module Propagation Delays												
t_{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.5		0.6		0.7		0.8		1.1	ns
t_{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		0.8		0.9		1.0		1.1		1.6	ns
t_{INYH}	Input Data Pad to Y High 3.3 V PCI		0.5		0.6		0.6		0.7		1.0	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t_{INYH}	Input Data Pad to Y High 3.3 V LVTTL		0.7		0.7		0.8		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		0.9		1.1		1.2		1.4		2.0	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-27 • **A54SX16A Timing Characteristics**
(Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)

Parameter	Description	–3 Speed[1] Min.	–3 Speed[1] Max.	–2 Speed Min.	–2 Speed Max.	–1 Speed Min.	–1 Speed Max.	Std. Speed Min.	Std. Speed Max.	–F Speed Min.	–F Speed Max.	Units
5 V PCI Output Module Timing[2]												
t_{DLH}	Data-to-Pad Low to High		2.2		2.5		2.8		3.3		4.6	ns
t_{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0		2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.2		2.5		2.8		3.3		4.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.8		3.2		3.6		4.2		5.9	ns
d_{TLH}[3]	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF
d_{THL}[3]	Delta High to Low		0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad Low to High		2.2		2.5		2.8		3.3		4.6	ns
t_{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		6.7		7.7		8.7		10.2		14.3	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H		1.9		2.2		2.5		2.9		4.1	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.5		2.9		3.3		3.9		5.4	ns
d_{TLH}[3]	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF
d_{THL}[3]	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF
d_{THLS}[3]	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 50 pF loading.*
3. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1 * V_{CCI} – 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. *Delays based on 35 pF loading.*

Table 2-28 • **A54SX32A Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	–3 Speed[1] Min.	–3 Speed[1] Max.	–2 Speed Min.	–2 Speed Max.	–1 Speed Min.	–1 Speed Max.	Std. Speed Min.	Std. Speed Max.	–F Speed Min.	–F Speed Max.	Units
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.9		1.1		1.2		1.4		1.9	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.9		1.1		1.2		1.4		1.9	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		1.4		1.6		1.8		2.1		2.9	ns
Input Module Predicted Routing Delays[3]												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1		1.4	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2		2.2		2.6		3.6	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-35 • **A54SX72A Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.6		0.7		0.8		1.1	ns
t_{INYL}	Input Data Pad to Y Low 5 V PCI		0.8		0.9		1.0		1.2		1.6	ns
t_{INYH}	Input Data Pad to Y High 5 V TTL		0.7		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 5 V TTL		0.9		1.1		1.2		1.4		1.9	ns
Input Module Predicted Routing Delays[3]												
t_{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.7	ns
t_{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.6		0.7		1	ns
t_{IRD3}	FO = 3 Routing Delay		0.5		0.7		0.8		0.9		1.3	ns
t_{IRD4}	FO = 4 Routing Delay		0.7		0.9		1		1.1		1.5	ns
t_{IRD8}	FO = 8 Routing Delay		1.2		1.5		1.7		2.1		2.9	ns
t_{IRD12}	FO = 12 Routing Delay		1.7		2.2		2.5		3		4.2	ns

Notes:

1. *All –3 speed grades have been discontinued.*
2. *For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
3. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-38 • **A54SX72A Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.6		1.8		2.1		2.4		3.4	ns
t_{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.5	ns
t_{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{QCKSW}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t_{QCKSW}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t_{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: **All –3 speed grades have been discontinued.*

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
141	NC	I/O	I/O	I/O
142	I/O	I/O	I/O	I/O
143	NC	I/O	I/O	I/O
144	I/O	I/O	I/O	I/O
145	V_{CCA}	V_{CCA}	V_{CCA}	V_{CCA}
146	GND	GND	GND	GND
147	I/O	I/O	I/O	I/O
148	V_{CCI}	V_{CCI}	V_{CCI}	V_{CCI}
149	I/O	I/O	I/O	I/O
150	I/O	I/O	I/O	I/O
151	I/O	I/O	I/O	I/O
152	I/O	I/O	I/O	I/O
153	I/O	I/O	I/O	I/O
154	I/O	I/O	I/O	I/O
155	NC	I/O	I/O	I/O
156	NC	I/O	I/O	I/O
157	GND	GND	GND	GND
158	I/O	I/O	I/O	I/O
159	I/O	I/O	I/O	I/O
160	I/O	I/O	I/O	I/O
161	I/O	I/O	I/O	I/O
162	I/O	I/O	I/O	I/O
163	I/O	I/O	I/O	I/O
164	V_{CCI}	V_{CCI}	V_{CCI}	V_{CCI}
165	I/O	I/O	I/O	I/O
166	I/O	I/O	I/O	I/O
167	NC	I/O	I/O	I/O
168	I/O	I/O	I/O	I/O
169	I/O	I/O	I/O	I/O
170	NC	I/O	I/O	I/O
171	I/O	I/O	I/O	I/O
172	I/O	I/O	I/O	I/O
173	NC	I/O	I/O	I/O
174	I/O	I/O	I/O	I/O
175	I/O	I/O	I/O	I/O

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
176	NC	I/O	I/O	I/O
177	I/O	I/O	I/O	I/O
178	I/O	I/O	I/O	QCLKD
179	I/O	I/O	I/O	I/O
180	CLKA	CLKA	CLKA	CLKA
181	CLKB	CLKB	CLKB	CLKB
182	NC	NC	NC	NC
183	GND	GND	GND	GND
184	V_{CCA}	V_{CCA}	V_{CCA}	V_{CCA}
185	GND	GND	GND	GND
186	PRA, I/O	PRA, I/O	PRA, I/O	PRA, I/O
187	I/O	I/O	I/O	V_{CCI}
188	I/O	I/O	I/O	I/O
189	NC	I/O	I/O	I/O
190	I/O	I/O	I/O	QCLKC
191	I/O	I/O	I/O	I/O
192	NC	I/O	I/O	I/O
193	I/O	I/O	I/O	I/O
194	I/O	I/O	I/O	I/O
195	NC	I/O	I/O	I/O
196	I/O	I/O	I/O	I/O
197	I/O	I/O	I/O	I/O
198	NC	I/O	I/O	I/O
199	I/O	I/O	I/O	I/O
200	I/O	I/O	I/O	I/O
201	V_{CCI}	V_{CCI}	V_{CCI}	V_{CCI}
202	NC	I/O	I/O	I/O
203	NC	I/O	I/O	I/O
204	I/O	I/O	I/O	I/O
205	NC	I/O	I/O	I/O
206	I/O	I/O	I/O	I/O
207	I/O	I/O	I/O	I/O
208	TCK, I/O	TCK, I/O	TCK, I/O	TCK, I/O

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	TMS	TMS	TMS
10	V_{CCI}	V_{CCI}	V_{CCI}
11	GND	GND	GND
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	NC	NC	NC
20	V_{CCA}	V_{CCA}	V_{CCA}
21	I/O	I/O	I/O
22	TRST, I/O	TRST, I/O	TRST, I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	GND	GND	GND
29	V_{CCI}	V_{CCI}	V_{CCI}
30	V_{CCA}	V_{CCA}	V_{CCA}
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	GND	GND	GND
37	I/O	I/O	I/O

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V_{CCI}	V_{CCI}	V_{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	PRB, I/O	PRB, I/O	PRB, I/O
55	I/O	I/O	I/O
56	V_{CCA}	V_{CCA}	V_{CCA}
57	GND	GND	GND
58	NC	NC	NC
59	I/O	I/O	I/O
60	HCLK	HCLK	HCLK
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	V_{CCI}	V_{CCI}	V_{CCI}
69	I/O	I/O	I/O
70	I/O	I/O	I/O
71	TDO, I/O	TDO, I/O	TDO, I/O
72	I/O	I/O	I/O
73	GND	GND	GND
74	I/O	I/O	I/O

176-Pin TQFP

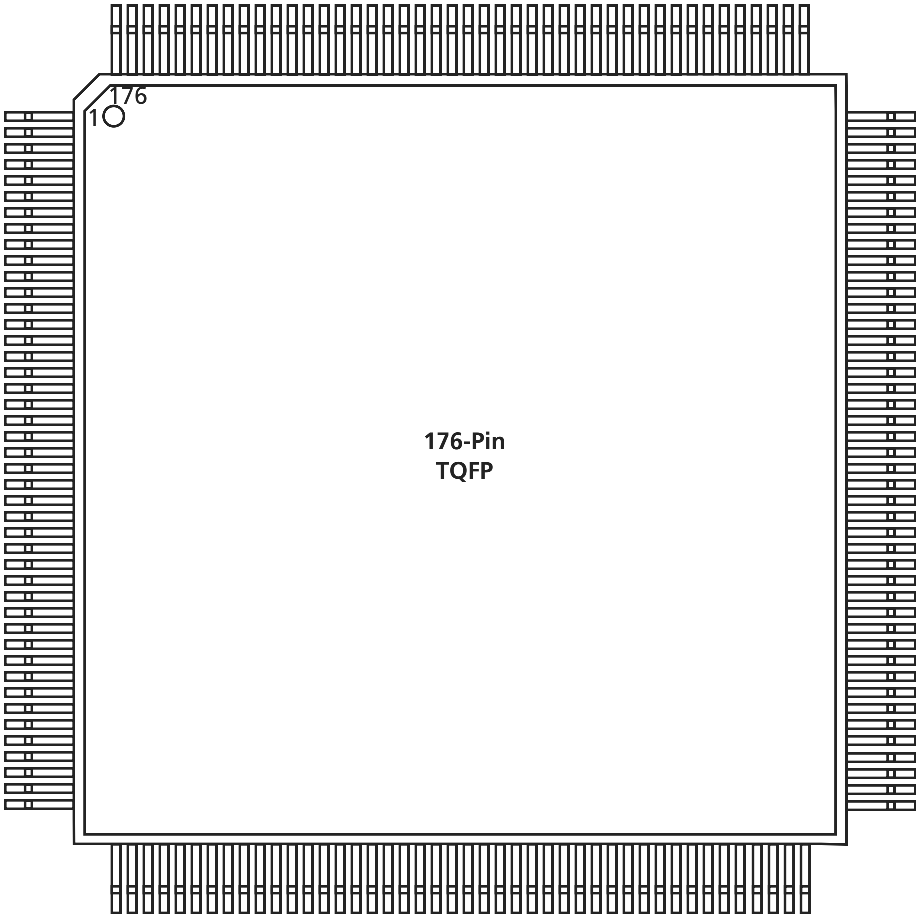


Figure 3-4 • **176-Pin TQFP (Top View)**

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.

176-Pin TQFP	
Pin Number	A54SX32A Function
1	GND
2	TDI, I/O
3	I/O
4	I/O
5	I/O
6	I/O
7	I/O
8	I/O
9	I/O
10	TMS
11	V_{CCI}
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	I/O
18	I/O
19	I/O
20	I/O
21	GND
22	V_{CCA}
23	GND
24	I/O
25	TRST, I/O
26	I/O
27	I/O
28	I/O
29	I/O
30	I/O
31	I/O
32	V_{CCI}
33	V_{CCA}
34	I/O
35	I/O
36	I/O

176-Pin TQFP	
Pin Number	A54SX32A Function
37	I/O
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	GND
45	I/O
46	I/O
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	V_{CCI}
53	I/O
54	I/O
55	I/O
56	I/O
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	PRB, I/O
65	GND
66	V_{CCA}
67	NC
68	I/O
69	HCLK
70	I/O
71	I/O
72	I/O

176-Pin TQFP	
Pin Number	A54SX32A Function
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	V_{CCI}
83	I/O
84	I/O
85	I/O
86	I/O
87	TDO, I/O
88	I/O
89	GND
90	I/O
91	I/O
92	I/O
93	I/O
94	I/O
95	I/O
96	I/O
97	I/O
98	V_{CCA}
99	V_{CCI}
100	I/O
101	I/O
102	I/O
103	I/O
104	I/O
105	I/O
106	I/O
107	I/O
108	GND

176-Pin TQFP	
Pin Number	A54SX32A Function
109	V_{CCA}
110	GND
111	I/O
112	I/O
113	I/O
114	I/O
115	I/O
116	I/O
117	I/O
118	I/O
119	I/O
120	I/O
121	I/O
122	V_{CCA}
123	GND
124	V_{CCI}
125	I/O
126	I/O
127	I/O
128	I/O
129	I/O
130	I/O
131	I/O
132	I/O
133	GND
134	I/O
135	I/O
136	I/O
137	I/O
138	I/O
139	I/O
140	V_{CCI}
141	I/O
142	I/O
143	I/O
144	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
A1	NC*	NC
A2	NC*	NC
A3	NC*	I/O
A4	NC*	I/O
A5	NC*	I/O
A6	I/O	I/O
A7	I/O	I/O
A8	I/O	I/O
A9	I/O	I/O
A10	I/O	I/O
A11	NC*	I/O
A12	NC*	I/O
A13	I/O	I/O
A14	NC*	NC
A15	NC*	I/O
A16	NC*	I/O
A17	I/O	I/O
A18	I/O	I/O
A19	I/O	I/O
A20	I/O	I/O
A21	NC*	I/O
A22	NC*	I/O
A23	NC*	I/O
A24	NC*	I/O
A25	NC*	NC
A26	NC*	NC
AA1	NC*	I/O
AA2	NC*	I/O
AA3	V_{CCA}	V_{CCA}
AA4	I/O	I/O
AA5	I/O	I/O
AA22	I/O	I/O
AA23	I/O	I/O
AA24	I/O	I/O
AA25	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
AA26	NC*	I/O
AB1	NC*	NC
AB2	V_{CCI}	V_{CCI}
AB3	I/O	I/O
AB4	I/O	I/O
AB5	NC*	I/O
AB6	I/O	I/O
AB7	I/O	I/O
AB8	I/O	I/O
AB9	I/O	I/O
AB10	I/O	I/O
AB11	I/O	I/O
AB12	PRB, I/O	PRB, I/O
AB13	V_{CCA}	V_{CCA}
AB14	I/O	I/O
AB15	I/O	I/O
AB16	I/O	I/O
AB17	I/O	I/O
AB18	I/O	I/O
AB19	I/O	I/O
AB20	TDO, I/O	TDO, I/O
AB21	GND	GND
AB22	NC*	I/O
AB23	I/O	I/O
AB24	I/O	I/O
AB25	NC*	I/O
AB26	NC*	I/O
AC1	I/O	I/O
AC2	I/O	I/O
AC3	I/O	I/O
AC4	NC*	I/O
AC5	V_{CCI}	V_{CCI}
AC6	I/O	I/O
AC7	V_{CCI}	V_{CCI}
AC8	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
AC9	I/O	I/O
AC10	I/O	I/O
AC11	I/O	I/O
AC12	I/O	QCLKA
AC13	I/O	I/O
AC14	I/O	I/O
AC15	I/O	I/O
AC16	I/O	I/O
AC17	I/O	I/O
AC18	I/O	I/O
AC19	I/O	I/O
AC20	V_{CCI}	V_{CCI}
AC21	I/O	I/O
AC22	I/O	I/O
AC23	NC*	I/O
AC24	I/O	I/O
AC25	NC*	I/O
AC26	NC*	I/O
AD1	I/O	I/O
AD2	I/O	I/O
AD3	GND	GND
AD4	I/O	I/O
AD5	I/O	I/O
AD6	I/O	I/O
AD7	I/O	I/O
AD8	I/O	I/O
AD9	V_{CCI}	V_{CCI}
AD10	I/O	I/O
AD11	I/O	I/O
AD12	I/O	I/O
AD13	V_{CCI}	V_{CCI}
AD14	I/O	I/O
AD15	I/O	I/O
AD16	I/O	I/O
AD17	V_{CCI}	V_{CCI}

Note: **These pins must be left floating on the A54SX32A device.*